

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2103	(golden or reference or test or calibration or ideal or perfect) near3 wafer with (lamp or laser or light)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:37
L2	15582	(golden or reference or test or calibration or ideal or perfect) near3 wafer and (lamp or laser or light)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:38
L3	4497	(golden or reference or test or calibration or ideal or perfect) near3 wafer and (lamp or laser or light) with (intensity or illumination)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:38
L4	615	(golden or reference or test or calibration or ideal or perfect) near3 wafer and (lamp or laser or light) with (intensity or illumination) and slope	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:39
L5	24	(golden or reference or test or calibration or ideal or perfect) near3 wafer and (lamp or laser or light) with (intensity or illumination) and slope with normal\$7	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:41
L6	3	(golden or reference or test or calibration or ideal or perfect) near3 wafer and (lamp or laser or light) with (intensity or illumination) and slope with normal\$7 and (color or colour)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:43
L7	26	(golden or reference or test or calibration or ideal or perfect) near3 (wafer or circuit or chip) and (lamp or laser or light) with (intensity or illumination) and slope with normal\$7 and (color or colour)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:43

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L8	6	(golden or reference or test or calibration or ideal or perfect) near3 (wafer or circuit or chip) and (lamp or laser or light) with (intensity or illumination) and slope with normal\$7 same (color or colour)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:46
L9	6	(golden or reference or test or calibration or ideal or perfect) near3 (wafer or circuit or chip or workpiece) and (lamp or laser or light) with (intensity or illumination) and slope with normal\$7 same (color or colour)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:52
L10	6	(golden or reference or test or calibration or ideal or perfect) near3 (wafer or circuit or chip or workpiece) and (lamp or laser or light) and slope with normal\$7 same (color or colour)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:52
L11	11	(golden or reference or test or calibration or ideal or perfect) near3 (wafer or circuit or chip or workpiece) and (lamp or laser or light) and slope with normal\$7 same (color or colour or red or green or blue)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:31
L12	760	250/559.45.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:57
L13	4	250/559.45.ccls. and slope with normal\$7	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:57
L14	0	250/559.45.ccls. and slope with normal\$7 same (color or colour or red or green or blue)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:57

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L15	996	356/237.4,237.5.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:58
L16	1	356/237.4,237.5.ccls. and slope with normal\$7 same (color or colour or red or green or blue)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:58
L17	3282	382/141,144,145,147,152.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 09:58
L18	0	382/141,144,145,147,152.ccls. and slope with normal\$7 same (color or colour or red or green or blue)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:01
L19	37796	(lamp or light or laser) with "same" with (intensity or illumination)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:02
L20	4273	(lamp or light or laser) with "same" with (intensity or illumination) and wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:02
L21	1731	(lamp or light or laser) with "same" with (intensity or illumination) and second near4 lamp	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:03

EAST Search History

L22	261	(lamp or light or laser) with "same" with (intensity or illumination) same second near4 lamp	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:03
L23	114	(lamp or light or laser) with "same" with (intensity or illumination) with second near4 lamp	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:03
L24	114	(lamp) with "same" with (intensity or illumination) with second near4 lamp	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:03
L25	3	(lamp) with "same" with (intensity or illumination) with second near4 lamp and inspection	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:04
L26	322	(lamp or light) with "same" with (intensity or illumination) with second near4 (lamp or light) and inspection	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:05
L27	1	(lamp or light) with "same" with (intensity or illumination) with second near4 (lamp or light) and inspection and recipe	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:12
L28	2	(lamp or light) with ("same" or closest) with (intensity or illumination) with second near4 (lamp or light) and inspection and recipe	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:14

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L29	2	(lamp or light) with ("same" or closest or nearest) with (intensity or illumination) with second near4 (lamp or light) and inspection and recipe	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:14
L30	2	(lamp or light) with ("same" or close\$2 or near\$3) with (intensity or illumination) with second near4 (lamp or light) and inspection and recipe	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:15
L31	2	(lamp or light or lase) with ("same" or close\$2 or near\$3) with (intensity or illumination) with second near4 (lamp or light or laser) and inspection and recipe	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:15
L32	2	(lamp or light or laser) with ("same" or close\$2 or near\$3) with (intensity or illumination) with second near4 (lamp or light or laser) and inspection near4 recipe	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:15
L33	328	(lamp or light or laser) and inspection near4 recipe	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:16
L34	26	(lamp or light or laser) and inspection near4 recipe with (intensity or illumination or brightness or lightness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:16
L35	13	(lamp or light or laser) with second and inspection near4 recipe with (intensity or illumination or brightness or lightness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:17

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L36	11	(lamp or light or laser) near4 second and inspection near4 recipe with (intensity or illumination or brightness or lightness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:18
L37	41	(lamp or light or laser) near4 second and inspection near4 recipe	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:22
L38	56	(lamp or light or laser) with setting and inspection near4 recipe	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:24
L39	5	(lamp or light or laser) with setting with (clos\$4 or "same" or match\$4 or near\$4) and inspection near4 recipe	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:26
L40	103	(lamp or light or laser) with (clos\$4 or "same" or match\$4 or near\$4) and inspection near4 recipe	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:26
L41	39	(lamp or light or laser) with (clos\$4 or "same" or match\$4 or near\$4)with (lightness or brightness or intensity or illumination) and inspection near4 recipe	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:27
L42	15	(lamp or light or laser) with (clos\$4 or "same" or match\$4 or near\$4)with (lightness or brightness or intensity or illumination) and inspection near4 recipe with (lightness or brightness or intensity or illumination)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:28

EAST Search History

L43	39	(lamp or light or laser) with (clos\$4 or "same" or match\$4 or near\$4)with (lightness or brightness or intensity or illumination) and inspection near4 recipe	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:30
L44	1	((lamp or light or laser) with (clos\$4 or "same" or match\$4 or near\$4)with (lightness or brightness or intensity or illumination) and inspection near4 recipe).clm.	US-PGPUB	OR	ON	2007/11/16 10:30
L45	1	((golden or reference or test or calibration or ideal or perfect) near3 (wafer or circuit or chip or workpiece) and (lamp or laser or light) and slope with normal\$7 same (color or colour or red or green or blue)).clm.	US-PGPUB	OR	ON	2007/11/16 10:31
L46	25	(dixon near4 david).in.	US-PGPUB	OR	ON	2007/11/16 10:32
L47	1	(dixon near4 david).in. and wafer	US-PGPUB	OR	ON	2007/11/16 10:32
L48	1	(dixon near4 david).in. and wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 10:32
L49	1	(lloyd near4 lee).in. and wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 11:25
L50	217	315/293.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 11:25
L51	0	315/293.ccls. and wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 11:26

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L52	49	315/293.ccls. and (intensity or brightness or lightness) with (similar or "same" or clos\$4 or near\$4 or match\$4)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 11:28
L53	30	315/293.ccls. and (intensity or brightness or lightness) near4 (similar or "same" or clos\$4 or near\$4 or match\$4)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 11:29
L54	0	315/293.ccls. and (intensity or brightness or lightness) near4 (similar or "same" or clos\$4 or near\$4 or match\$4) and inspect\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/16 11:29


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- ☐ 3. Integrated-optic dispersion slope equalizer for N/spl times/ several tens transmission
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- ☐ 4. Ideal rectangular cross-section Si-Fin channel double-gate MOSFETs fal orientation-dependent wet etching
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